

<b>Notice of References Cited</b>	Application/Control No. 10/815,518		Applicant(s)/Patent Under Reexamination FULTZ ET AL.	
	Examiner SHANTO M. ABEDIN		Art Unit 2436	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0097574	05-2003	Upton, Mitch	713/183
*	B	US-2003/0200465	10-2003	Bhat et al.	713/202
*	C	US-2005/0108521 A1	05-2005	Silhavy et al.	713/156
*	D	US-7,334,254 B1	02-2008	Boydston et al.	726/2
*	E	US-7,209,970 B1	04-2007	Everson et al.	709/229
*	F	US-7,363,487 B2	04-2008	Venkataramappa et al.	713/150
*	G	US-7,178,163 B2	02-2007	Reeves, Jr., Charles R.	726/2
*	H	US-5,604,490	02-1997	Blakley et al.	726/5
*	I	US-6,681,330 B2	01-2004	Bradford et al.	726/3
*	J	US-7,249,375 B2	07-2007	Bhatia et al.	726/8
*	K	US-7,178,150 B1	02-2007	Ahmad et al.	719/313
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	W					
	X					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.